FemtoClocks™ Crystal-to-3.3V LVPECL Frequency Synthesizer

DATA SHEET

Description

The 843001-21 is a a highly versatile, low phase noise LVPECL Synthesizer which can generate low jitter reference clocks for a variety of communications applications. The dual crystal interface allows the synthesizer to support up to two communications standards in a given application (i.e. 1GB Ethernet with a 25MHz crystal and 1Gb Fibre Channel using a 26.5625MHz crystal). The rms phase jitter performance is typically less than 1ps, thus making the device acceptable for use in demanding applications such as OC48 SONET and 10Gb Ethernet. The 843001-21 is packaged in a small 24-pin TSSOP package.

Features

- One 3.3Vdifferential LVPECL output pair and one LVCMOS/LVTTL single-ended reference clock output
- Selectable crystal oscillator interface or LVCMOS/LVTTL single-ended input
- VCO range: 560MHz 700MHz
- Supports the following applications: SONET, Ethernet, Fibre Channel, Serial ATA, and HDTV
- Selectable ÷1 or ÷2 operation
- RMS phase jitter @ 622.08MHz (12kHz 20MHz): 0.80ps (typical)

Offset	Noise Power
100Hz	60.3 dBc/Hz
1kHz	88.5 dBc/Hz
10kHz	111.9 dBc/Hz
100kHz	113.0 dBc/Hz

- Full 3.3V supply mode
- 0°C to 70°C ambient operating temperature
- Available in lead-free (RoHS 6) package

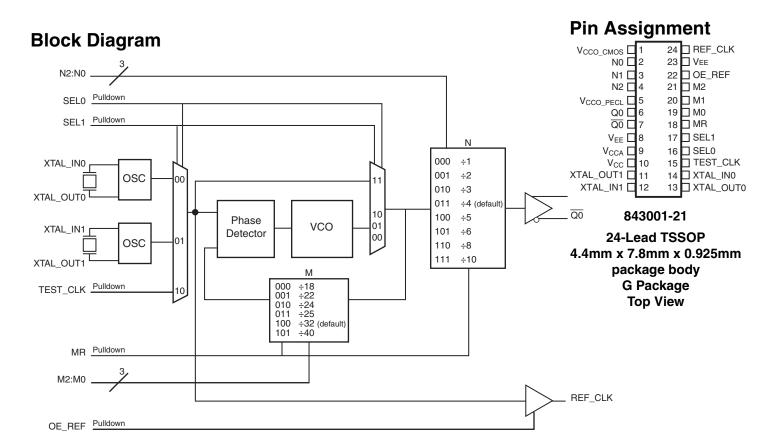




Table 1. Pin Descriptions

Number	Name	Т	уре	Description
1	V _{CCO_CMOS}	Power		Output supply pin for REF_CLK output.
2, 3	N0, N1	Input	Pullup	Output divider select pins. Default ÷4. LVCMOS/LVTTL interface levels.
4	N2	Input	Pulldown	See Table 3C.
5	V _{CCO_PECL}	Power		Output supply pin for LVPECL output.
6, 7	Q0, Q0	Output		Differential output pair. LVPECL interface levels.
8, 23	V _{EE}	Power		Negative supply pins.
9	V _{CCA}	Power		Analog supply pin.
10	V _{CC}	Power		Core supply pin.
11,	XTAL_OUT1,	Input		Parallel resonant crystal interface.
12	XTAL_IN1			XTAL_OUT1 is the output, XTAL_IN1 is the input.
13,	XTAL_OUT0,	Input		Parallel resonant crystal interface.
14	XTAL_IN0	•		XTAL_OUT0 is the output, XTAL_IN0 is the input.
15	TEST_CLK	Input	Pulldown	LVCMOS/LVTTL clock input.
16, 17	SEL0, SEL1	Input	Pulldownp	Input MUX select pins. LVCMOS/LVTTL interface levels. See Table 3D.
18	MR	Input	Pulldown	Active HIGH Master Reset. When logic HIGH, the internal dividers are reset causing the true output Q0 to go low and the inverted output $\overline{\text{Q0}}$ to go high. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS/LVTTL interface levels.
19, 20	M0, M1	Input	Pulldown	Feedback divider select pins. Default ÷32. See Table 3B
21	M2	Input	Pullup	LVCMOS/LVTTL interface levels.
22	OE_REF	Input	Pulldown	Reference clock output enable. Default Low. LVCMOS/LVTTL interface levels.
24	REF_CLK	Output		Reference clock output. LVCMOS/LVTTL interface levels.

NOTE: Pullup and Pulldown refer to intenal input resistors. See Table 2, Pin Characteristics, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ
R _{OUT}	Output Impedance			7		Ω



Function Tables

Table 3A. Common Configuration Table

Input	M Divider	N Divider		Output Frequency	
Reference Clock (MHz)	Value	Value	VCO (MHz)	(MHz)	Application
27	22	8	594	74.25	HDTV
24.75	24	8	594	74.25	HDTV
14.8351649	40	8	593.4066	74.1758245	HDTV
19.44	32	4	622.08	155.52	SONET
19.44	32	8	622.08	77.76	SONET
19.44	32	1	622.08	622.08	SONET
19.44	32	2	622.08	311.04	SONET
19.53125	32	4	625	156.25	10 GigE
25	25	5	625	125	1 GigE
25	25	10	625	62.5	1 GigE
25	24	6	600	100	PCI Express
25	24	4	600	150	SATA
25	24	8	600	75	SATA
26.5625	24	6	637.5	106.25	Fibre Channel 1
26.5625	24	3	637.5	212.5	4 Gig Fibre Channel
26.5625	24	4	637.5	159.375	10 Gig Fibre Channel
31.25	18	5	562.5	187.5	12 GigE

Table 3B. Programmable M Output Divider Function Table

	Inputs		M Divider - Value	Input Frequency (MHz	
M2	М1	МО		Minimum	Maximum
0	0	0	18	31.1	38.9
0	0	1	22	25.5	31.8
0	1	0	24	23.3	29.2
0	1	1	25	22.4	28.0
1	0	0	32	17.5	21.9
1	0	1	40	14.0	17.5

Table 3C. Programmable N Output Divider Function Table

	Inputs		M Divider
N2	N1	N0	Value
0	0	0	1
0	0	1	2
0	1	0	3

	Inputs		M Divider
N2	N1	N0	Value
0	1	1	4
1	0	0	5



	Inputs	M Divider	
N2	N1	N0	Value
1	0	1	6
1	1	0	8
1	1	1	10

Table 3D. Bypass Mode Function Table

Inputs			
SEL1	SEL0	Reference	PLL Mode
0	0	XTAL0	1
0	1	XTAL1	2
1	0	TEST_CLK	8
1	1	TEST_CLK1	10



Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characterisitcs* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V _{CC}	4.6V
Inputs, V _I	-0.5V to V _{CC} + 0.5V
Outputs, I _O (LVPECL) Continuous Current Surge Current	50mA 100mA
Outputs, V _O (LVCMOS)	-0.5V to V _{CCO_CMOS} + 0.5V
Package Thermal Impedance, θ_{JA}	70°C/W (0 mps)
Storage Temperature, T _{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 4A. Power Supply DC Characteristics, $V_{CC} = V_{CCA} = V_{CCO_CMOS} = V_{CCO_PECL} = 3.3V \pm 5\%$, $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{CC}	Core Supply Voltage		3.135	3.3	3.465	V
V _{CCA}	Analog Supply Voltage		3.135	3.3	3.465	V
V _{CCO_PECL} , V _{CCO_CMOS}	Output Supply Voltage		3.135	3.3	3.465	V
I _{EE}	Power Supply Current				170	mA
I _{CCA}	Analog Supply Current				11	mA
I _{CCO_PECL} , I _{CCO_CMOS}	Output Supply Current				8	mA



Table 4B. LVCMOS/LVTTL DC Characteristics, $V_{CC} = V_{CCA} = V_{CCO_CMOS} = 3.3V \pm 5\%$, $T_A = 0^{\circ}C$ to $70^{\circ}C$

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V _{IH}	Input High Voltage			2		V _{CC} + 0.3	V
V _{IL}	Input Low Voltage	SEL0, SEL1, OE_REF, N0:N2, MR, M0:M2		-0.3		0.8	V
		TEST_CLK		-0.3		1.3	V
I _{IH}	Input High Current	TEST_CLK, M0, M1, N2, MR, OE_REF, SEL0, SEL1	V _{CC} = V _{IN} = 3.465V			150	μА
		M2, N0, N1	$V_{CC} = V_{IN} = 3.465V$			5	μΑ
կլ	I _{II} Input Low Current	TEST_CLK, M0, M1, N2, MR, OE_REF, SEL0, SEL1	V _{CC} = 3.465V, V _{IN} = 0V	-5			μΑ
		M2, N0, N1	$V_{CC} = 3.465V,$ $V_{IN} = 0V$	-150			μΑ
V _{OH}	Output High Voltage: NOTE 1	REF_CLK		2.6			V
V _{OL}	Output Low Voltage: NOTE 1	REF_CLK				0.5	V

NOTE 1: Output terminated with 50Ω to $V_{CCO_CMOS}/2$. See Parameter Measurement Information Section, ""3.3V LVCMOS Output Load Test Circuit Diagram"".

Table 4C. LVPECL DC Characteristics, $V_{CC} = V_{CCA} = V_{CCO_PECL} = 3.3V \pm 5\%$, $T_A = 0^{\circ}C$ to $70^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{OH}	Output High Current; NOTE 1		V _{CCO} – 1.4		V _{CCO} – 0.9	μΑ
V _{OL}	Output Low Current; NOTE 1		V _{CCO} - 2.0		V _{CCO} – 1.7	μΑ
V _{SWING}	Peak-toPeak Output Voltage Swing		0.6		1.0	V

NOTE 1: Outputs termination with 50 Ω to VCCO_PECL - 2V.

Table 5. Crystal Characteristics

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation			Fundamenta	I	
Frequency		12		40	MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF

NOTE: Characterized using an 18pF parallel resonant crystal.



AC Electrical Characteristics

Table 6. AC Characteristics, $V_{CC} = V_{CCA} = V_{CCO_CMOS} = V_{CCO_PECL} = 3.3V \pm 5\%$, $T_A = 0$ °C to 70°C

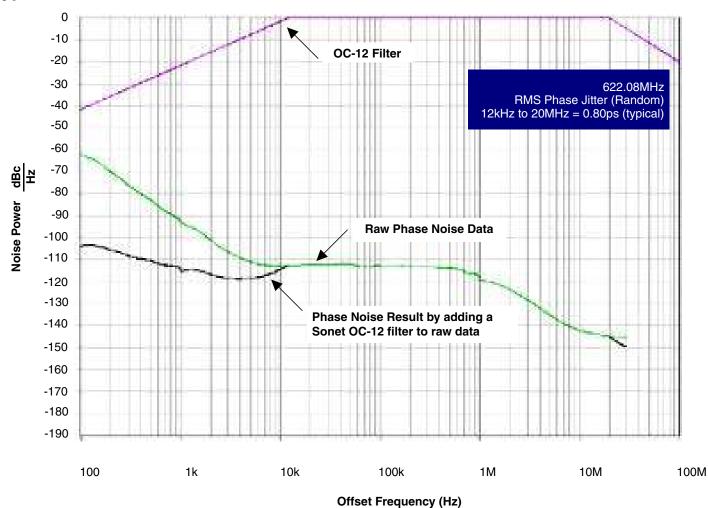
Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f _{OUT}	Output Frequency			56		700	MHz
t _{PD}	Propagation Delay; TEST_CLK to NOTE 1 REF_CLK			2.3		2.8	ns
fjit(Ø)	RMS Phase Jitter, (Random); NOTE 2, 3		622.08MHz, (12kHz – 20MHz)		0.80		ps
t _{VCO}	PLL VCO Lock Range			560		700	MHz
+ /+	Output	Q0, Q0	20% to 80%	200		500	ps
t_R / t_F	Rise/Fall Time	REF_CLK	20% to 80%	300		800	ps
odc	Outrout Duty Cycle	Q0, Q0		45		55	%
	Output Duty Cycle REF_CLK			44		56	%

NOTE 1: Measured from the $V_{CC}/2$ of the input to $V_{CCO\ CMOS}/2$ of the output.

NOTE 2: Phase jitter measured using a 19.44MHz quartz crystal.

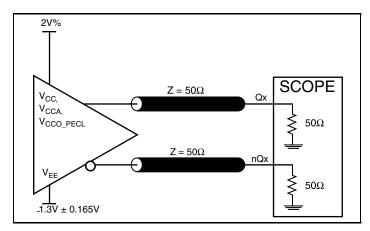
NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

Typical Phase Noise at 622.08MHz

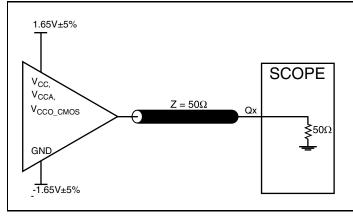




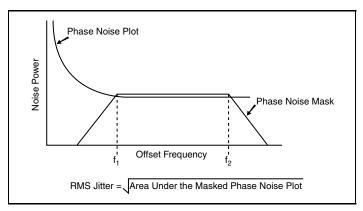
Parameter Measurement Information



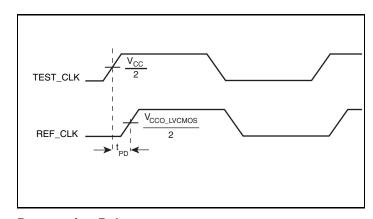
3.3V LVPECL Output Load AC Test Circuit



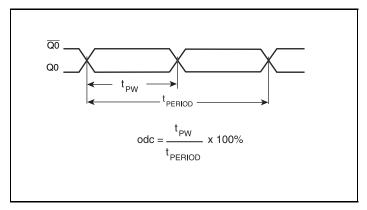
3.3V LVCMOS Output Load AC Test Circuit



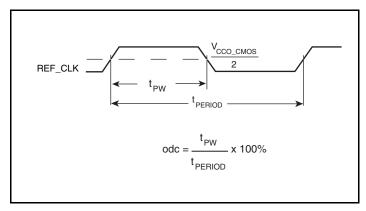
RMS Phase Jitter



Propagation Delay



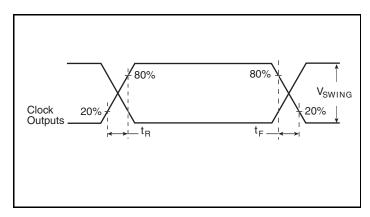
LVPECL Output Duty Cycle/Pulse Width/Period

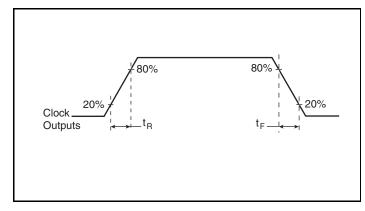


LVCMOS Output Duty Cycle/Pulse Width/Period



Parameter Measurement Information, continued





LVPECL Output Rise/Fall Time

LVCMOS Output Rise/Fall Time

Application Information

Power Supply Filtering Technique

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. The 843001-21 provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL. $V_{CC,}\,V_{CCA}$ and $V_{CCO_{_X}}$ should be individually connected to the power supply plane through vias, and bypass capacitors should be used for each pin. To achieve optimum jitter performance, power supply isolation is required. Figure 1 illustrates how a 10Ω resistor along with a $10\mu F$ and a $.01\mu F$ bypass capacitor should be connected to each V_{CCA} pin.

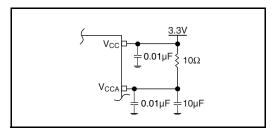


Figure 1. Power Supply Filtering



Crystal Input Interface

The 843001-21 has been characterized with 18pF parallel resonant crystals. The capacitor values shown in *Figure 2* below

were determined using a 19.44MHz, 18pF parallel resonant crystal and were chosen to minimize the ppm error.

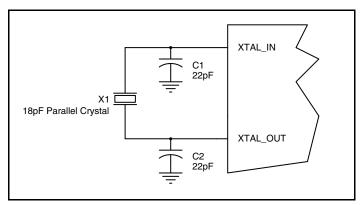


Figure 2. Crystal Input Interface

LVCMOS to XTAL Interface

The XTAL_IN input can accept a single-ended LVCMOS signal through an AC coupling capacitor. A general interface diagram is shown in *Figure 3*. The XTAL_OUT pin can be left floating. The input edge rate can be as slow as 10ns. For LVCMOS inputs, it is recommended that the amplitude be reduced from full swing to half swing in order to prevent signal interference with the power rail and to reduce noise. This configuration requires that the output

impedance of the driver (Ro) plus the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First, R1 and R2 in parallel should equal the transmission line impedance. For most 50Ω applications, R1 and R2 can be 100Ω . This can also be accomplished by removing R1 and making R2 50Ω .

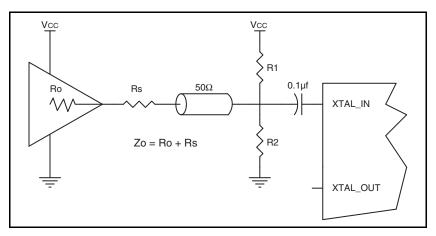


Figure 3. General Disgram for LVCMOS Driver to XTAL Input Interface



Recommendations for Unused Input and Output Pins

Inputs:

Crystal Inputs:

For applications not requiring the use of the crystal oscillator input, both XTAL_IN and XTAL_OUT can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from XTAL_IN to ground.

TEST_CLK Input:

For applications not requiring the use of the test clock, it can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from the TEST_CLK to ground.

LVCMOS Control Pins:

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A $1k\Omega$ resistor can be used.

Outputs:

LVPECL Output:

All unused LVPECL outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

LVCMOS Output:

All unused LVCMOS output can be left floating. We recommend that there is no trace attached.

Termination for 3.3V LVPECL Outputs

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

FOUT and \overline{FOUT} are low impedance follower outputs that generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to drive 50Ω

transmission lines. Matched impedance techniques should be used to maximize operating frequency and minimize signal distortion. *Figures 4A and 4B* show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

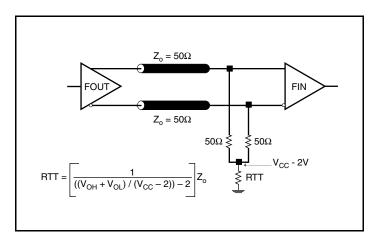


Figure 4A. 3.3V LVPECL Output Termination

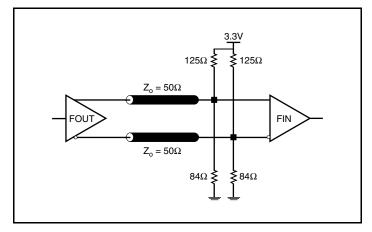


Figure 4B. 3.3V LVPECL Output Termination



Power Considerations

This section provides information on power dissipation and junction temperature for the ICS843001.21. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the 843001-21 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for V_{CC} = 3.3V + 5% = 3.465V, which gives worst case results.

NOTE: Please refer to Section 3 for details on calculating power dissipated in the load.

- Power (core)_{MAX} = V_{CC_MAX} * I_{EE_MAX} = 3.465V * 170mA = 589.05mW
- Power (outputs)_{MAX} = 30mW/Loaded Output pair

Total Power_MAX (3.3V, with all outputs switching) = 589.05mW + 30mW = 619.05mW

2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for Tj is as follows: Tj = θ_{JA} * Pd_total + T_A

Tj = Junction Temperature

 θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_total = Total Device Power Dissipation (example calculation is in section 1 above)

 T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming a moderate air flow of 1 meter per second and a multi-layer board, the appropriate value is 65°C/W per Table 7below.

Therefore, Tj for an ambient temperature of 70°C with all outputs switching is:

 $70^{\circ}\text{C} + 0.619\text{W} * 65^{\circ}\text{C/W} = 110.2^{\circ}\text{C}$. This is below the limit of 125°C .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

Table 7. Thermal Resitance θ_{JA} for 24 Lead TSSOP, Forced Convection

$ heta_{JA}$ vs. Air Flow				
Meters per Second	0	1	2.5	
Multi-Layer PCB, JEDEC Standard Test Boards	70°C/W	65	62	



3. Calculations and Equations.

The purpose of this section is to derive the power dissipated into the load.

LVPECL output driver circuit and termination are shown in Figure 5.

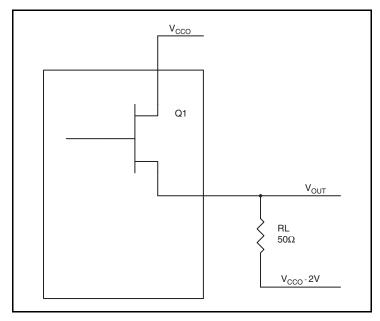


Figure 5. LVPECL Driver Circuit and Termination

To calculate worst case power dissipation into the load, use the following equations which assume a 50Ω load, and a termination voltage of V_{CCO} - 2V.

- For logic high, $V_{OUT} = V_{OH_MAX} = V_{CCO_MAX} 0.9V$ $(V_{CCO_MAX} - V_{OH_MAX}) = 0.9V$
- For logic low, $V_{OUT} = V_{OL_MAX} = V_{COO_MAX 1.7V}$ $(V_{CCO_MAX} - V_{OL_MAX}) = 1.7V$

Pd_H is power dissipation when the output drives high.

Pd_L is the power dissipation when the output drives low.

$$Pd_{-}H = [(V_{OH_MAX} - (V_{CCO_MAX} - 2V))/R_{.}] * (V_{CCO_MAX} - V_{OH_MAX}) = [(2V - (V_{CCO_MAX} - V_{OH_MAX}))/R_{.}] * (V_{CCO_MAX} - V_{OH_MAX}) = [(2V - 0.9V)/50\Omega] * 0.9V = 19.8mW$$

$$Pd_{L} = [(V_{OL_MAX} - (V_{CCO_MAX} - 2V))/R_{i}] * (V_{CCO_MAX} - V_{OL_MAX}) = [(2V - (V_{CCO_MAX} - V_{OL_MAX}))/R_{i}] * (V_{CCO_MAX} - V_{OL_MAX}) = [(2V - 1.7V)/50\Omega] * 1.7V = 10.2mW$$

Total Power Dissipation per output pair = Pd_H + Pd_L = **30mW**



Reliability Information

Table 8. θ_{JA} vs. Air Flow Table for a 24 Lead TSSOP

θ_{JA} vs. Air Flow					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	70°C/W	65	62		

Transistor Count

The transistor count for 843001-21 is: 4057

Package Outline and Package Dimension

Package Outline - G Suffix for 24 Lead TSSOP

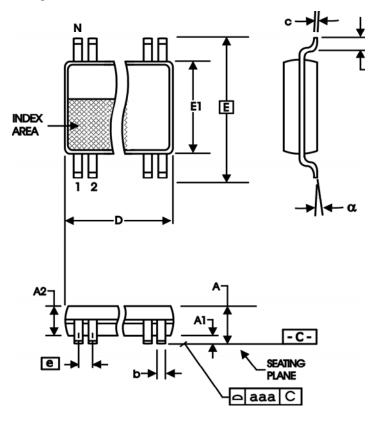


Table 9. Package Dimensions

All Dim	nensions in Mi	Ilimeters		
Symbol	Minimum Maximum			
N	24			
Α		1.20		
A 1	0.5	0.15		
A2	0.80	1.05		
b	0.19	0.30		
С	0.09	0.20		
D	7.70	7.90		
E	6.40	Basic		
E1	4.30	4.50		
е	0.65	Basic		
L	0.45	0.75		
α	0° 8°			
aaa	0.10			

Reference Document: JEDEC Publication 95, MO-153



Ordering Information

Table 10. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
843001AG-21LF	ICS843001A21L	"Lead-Free" 24 Lead TSSOP	Tube	0°C to 70°C
843001AG-21LFT	ICS843001A21L	"Lead-Free" 24 Lead TSSOP	Tape & Reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.



Revision History Sheet

Rev	Table	Page	Description of Change	Date
Α	T10	1 14	Features Section - added Lead-Free bullet. Ordering Information table - added Lead-Free marking.	2/8/05
A	T3C	3 9 10	Programmable N Output Divider Function Table - corrected heading from M Divide Value to N Divide value. Added Recommendations for Unused Input and Output Pins. Ordering Information Table - added lead-free note.	10/26/05
Α		1 9 10	General Description - corrected crystal frequency from 25.5625MHz crystal to 26.5625MHz crystal. Added LVCMOS Output RiseFall Time Diagram. Added LVCMOS to XTAL Interface section. Updated format throughout the datasheet.	3/15/07
Α	T10	15	Ordering Information - removed leaded devices. Updated data sheet information.	4/6/15



Corporate Headquarters

6024 Silver Creek Valley Road San Jose, CA 95138 USA Sales

1-800-345-7015 or 408-284-8200

Fax: 408-284-2775 www.IDT.com

Tech Support

email: clocks@idt.com

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